

RoHS Compliant Product
A suffix of "-C" specifies halogen & lead-free

DESCRIPTION

The miniature surface mount MOSFETs utilize high cell density process. Low $R_{DS(on)}$ assures minimal power loss and conserves energy, making this device ideal for use in power management circuitry.

FEATURES

- Low $R_{DS(on)}$ provides higher efficiency and extends battery life.
- Fast Switch.
- Low Gate Charge.
- Miniature SC-59 Surface Mount Package Saves Board Space.

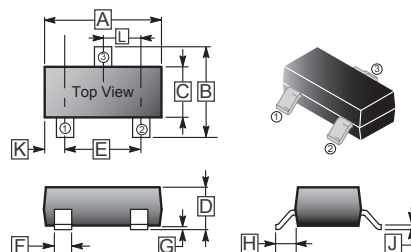
APPLICATION

Voltage control small signal switch, power management in portable and battery-powered products such as computer portable electronics and other battery power application.

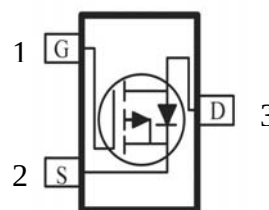
PACKAGE INFORMATION

Package	MPQ	Leader Size
SC-59	3K	7' inch

SC-59



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	2.70	3.10	G	0.10	REF.
B	2.25	3.00	H	0.40	REF.
C	1.30	1.70	J	0.10	0.20
D	1.00	1.40	K	0.45	0.55
E	1.70	2.30	L	0.85	1.15
F	0.35	0.50			



MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DS}	-60	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current ¹	$T_A = 25^\circ\text{C}$	I_D	-1.7	A
	$T_A = 70^\circ\text{C}$		-1.4	
Pulsed Drain Current ²		I_{DM}	± 15	A
Continuous Source Current (Diode Conduction) ¹		I_S	-1.7	A
Power Dissipation ¹	$T_A = 25^\circ\text{C}$	P_D	1.3	W
	$T_A = 70^\circ\text{C}$		0.8	
Operating Junction and Storage Temperature Range		T_J, T_{STG}	-55 ~ 150	$^\circ\text{C}$
Thermal Resistance Data				
Maximum Junction to Ambient ¹	$t \leq 5 \text{ sec}$	$R_{\theta JA}$	100	$^\circ\text{C/W}$
	Steady-State		166	

Notes:

1. Surface Mounted on 1" x 1" FR4 Board.
2. Pulse width limited by maximum junction temperature.

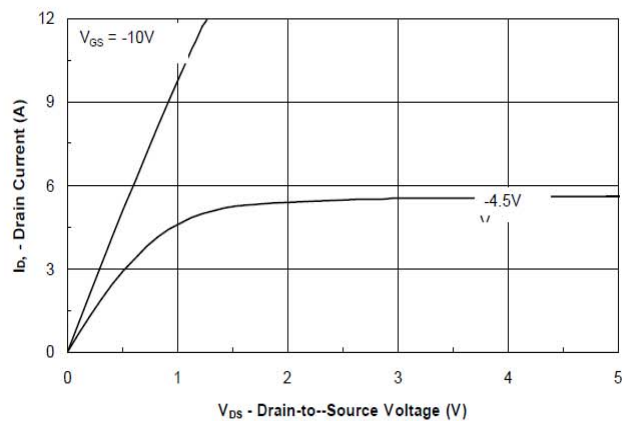
ELECTRICAL CHARACTERISTICS ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Static						
Zero Gate Voltage Drain Current	I_{DSS}	-	-	-1	μA	$V_{DS} = -48\text{V}, V_{GS}=0$
		-	-	-10		$V_{DS} = -48\text{V}, V_{GS}=0, T_J=55^\circ\text{C}$
Gate-Body Leakage	I_{GSS}	-	-	± 100	nA	$V_{DS}=0, V_{GS}= \pm 20\text{V}$
Gate-Threshold Voltage	$V_{GS(th)}$	-1	-2.1	-3.5	V	$V_{DS}=V_{GS}, I_D = -250\mu\text{A}$
On-State Drain Current ¹	$I_{D(ON)}$	-8	-	-	A	$V_{DS} = -5\text{V}, V_{GS}= -10\text{V}$
Drain-Source On-Resistance ¹	$R_{DS(ON)}$	-	300	381	m Ω	$V_{GS}= -10\text{V}, I_D = -1.6\text{A}$
		-	450	561		$V_{GS}= -4.5\text{V}, I_D = -1.3\text{A}$
Forward Transconductance ¹	g_{FS}	-	8	-	S	$V_{DS}= -15\text{V}, I_D = -1.6\text{A}$
Diode Forward Voltage	V_{SD}	-	-	-1.2	V	$I_S = -2.5\text{A}, V_{GS}=0$
Dynamic ²						
Total Gate Charge	Q_g	-	18	-	nC	$I_D = -1.6\text{A}$ $V_{DS}= -30\text{V}$ $V_{GS}= -4.5\text{V}$
Gate-Source Charge	Q_{gs}	-	5	-		
Gate-Drain Charge	Q_{gd}	-	2	-		
Turn-On Delay Time	$T_{d(ON)}$	-	8	-	nS	$V_{DD}= -30\text{V}$ $V_{GEN}= -10\text{V}$ $R_G=6\Omega$ $I_D = -1\text{A}$ $R_L=30\Omega$
Rise Time	T_r	-	10	-		
Turn-Off Delay Time	$T_{d(OFF)}$	-	35	-		
Fall Time	T_f	-	12	-		

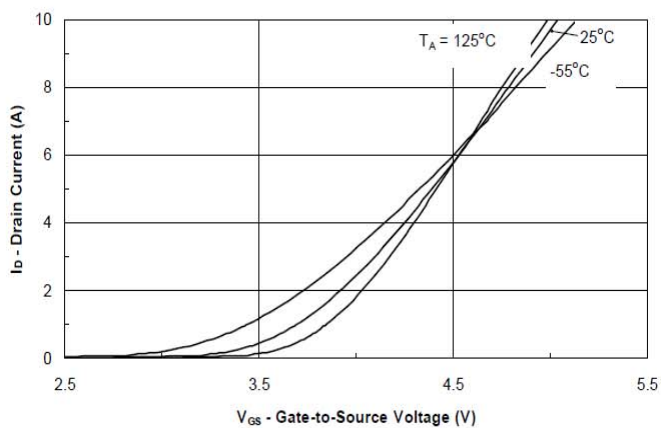
Notes:

1. Pulse test : $PW \leq 300 \mu\text{s}$ duty cycle $\leq 2\%$.
2. Guaranteed by design, not subject to production testing.

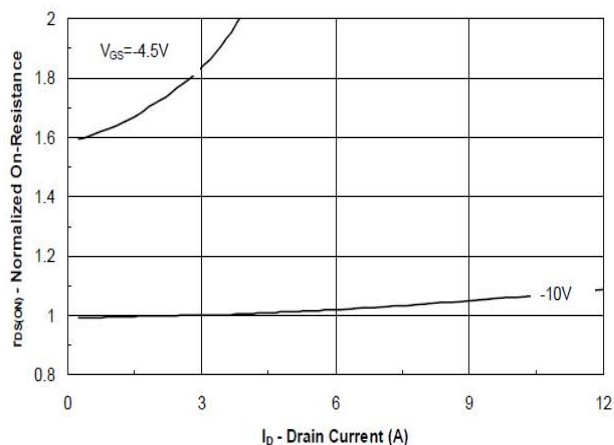
CHARACTERISTIC CURVE



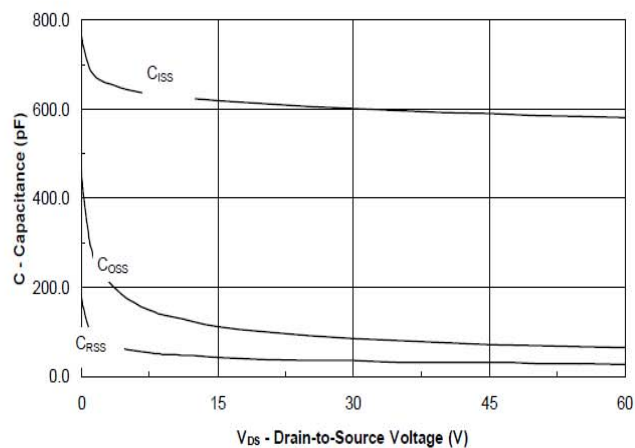
Output Characteristics



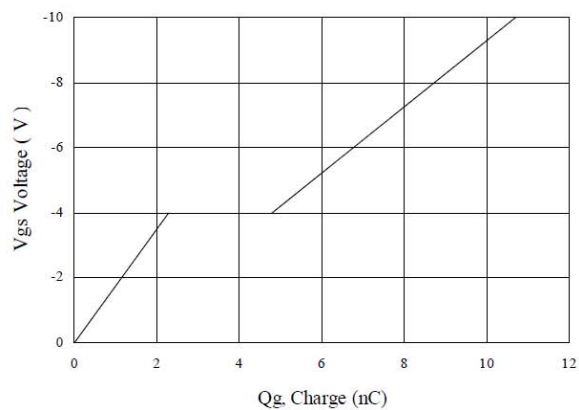
Transfer Characteristics



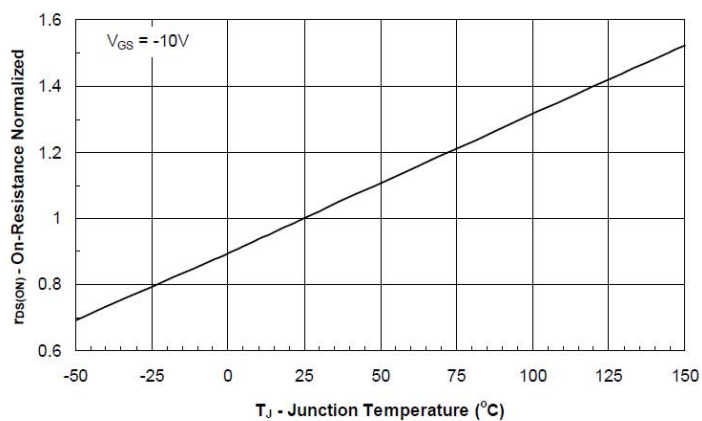
On-Resistance vs. Drain Current



Capacitance

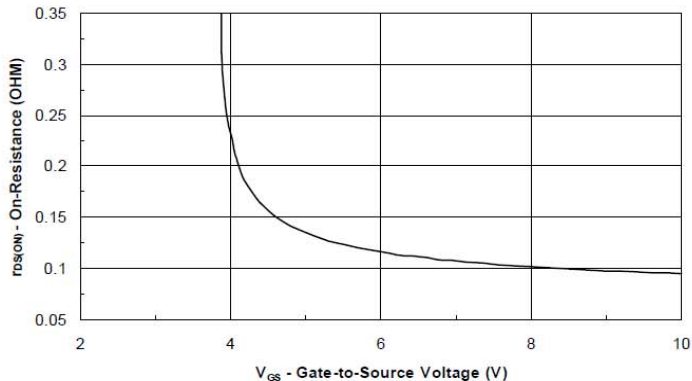
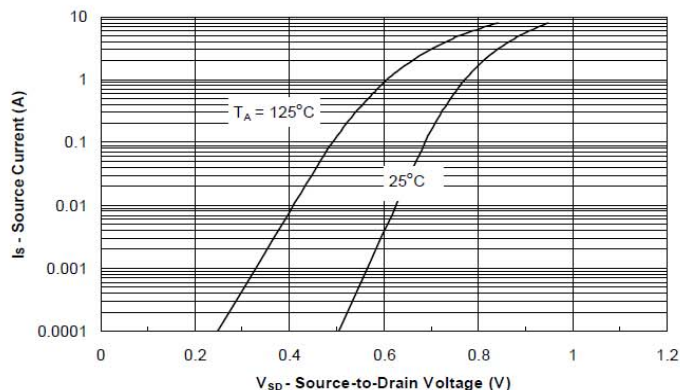


Gate Charge

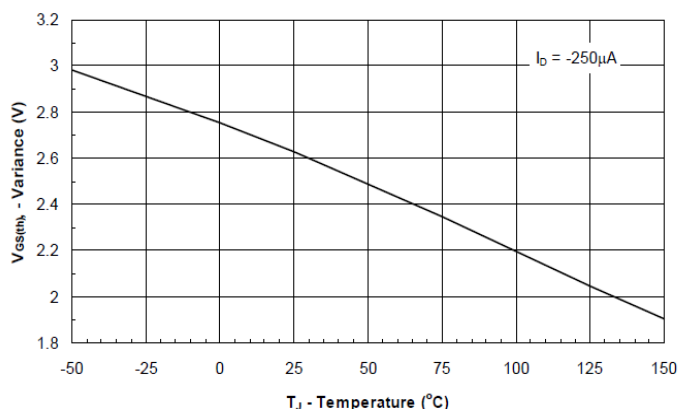


On-Resistance vs. Junction Temperature

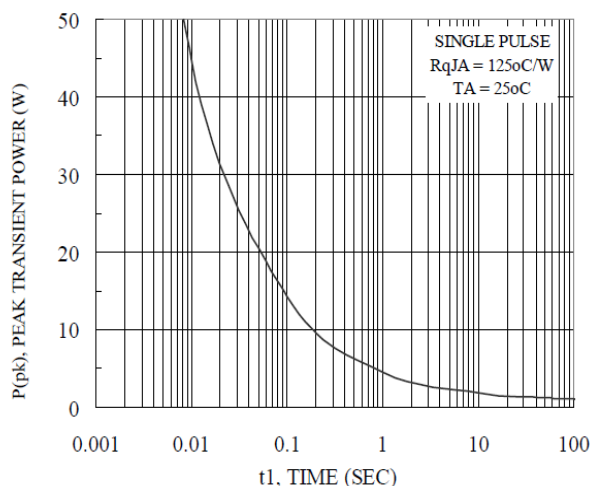
CHARACTERISTIC CURVE



Source-Drain Diode Forward Voltage



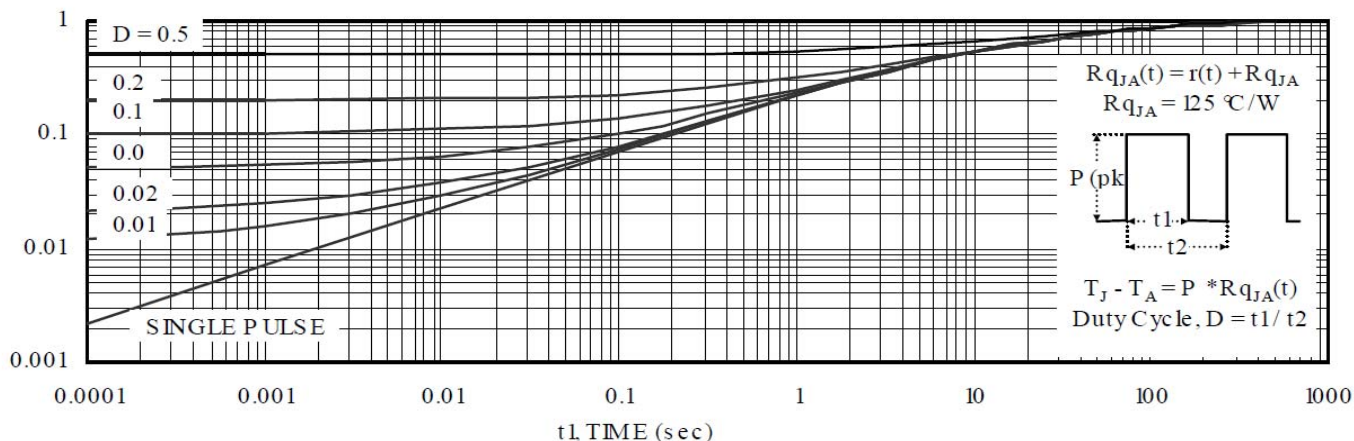
On-Resistance vs Gate-to-Source Voltage



Threshold Voltage

Single Pulse Power

Normalized Thermal Transient Junction to Ambient



Normalized Thermal Transient Impedance, Junction-to-Ambient